TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74VHC20F, TC74VHC20FN, TC74VHC20FT

#### **DUAL 4-INPUT NAND GATE**

The TC74VHC20 is an advanced high speed CMOS 4-INPUT NAND GATE fabricated with silicon gate C2MOS technology. It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

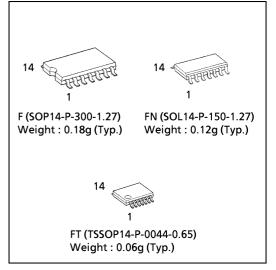
The internal circuit is composed of 3 stages including a buffer output, which provide high noise immunity and stable output.

An input protection circuit ensures that 0 to 5.5V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5V to 3V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

#### FEATURES:

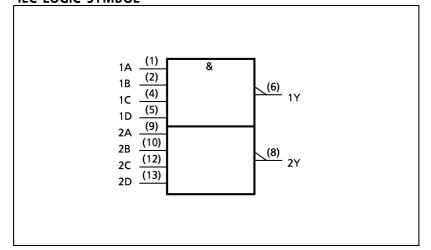
- High Speed······ $t_{pd}$  = 3.3ns(typ.) at  $V_{CC}$  = 5V
- Low Power Dissipation ··········· $I_{CC} = 2\mu A(Max.)$  at Ta = 25°C
- High Noise Immunity..... $V_{NIH} = V_{NII} = 28\% V_{CC}$  (Min.)
- Power Down Protection is provided on all inputs.
- Balanced Propagation Delays  $\cdots t_{pLH} \simeq t_{pHL}$
- Wide Operating Voltage Range···· V<sub>CC</sub> (opr) = 2V~5.5V
- Pin and Function Compatible with 74ALS20

(Note) The JEDEC SOP (FN) is not available in Japan.



#### **PIN ASSIGNMENT** 14 V<sub>CC</sub> 1A 1 1B 2 13 2D NC 3 12 2C 1C 4 NC 11 1D 5 10 2B 6 1Y 2A GND 7 8 2Y (TOP VIEW)

# **IEC LOGIC SYMBOL**



### TRUTH TABLE

	INP	OUTPUT		
Α	В	C	D	Υ
L	Х	Х	Х	Н
Х	L	Х	Х	Н
Х	Х	L	Х	Н
Х	Х	Х	L	Н
Н	Н	Н	Н	L

X : Don't Care

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### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V <sub>cc</sub>	-0.5~7.0	V
DC Input Voltage	V <sub>IN</sub>	-0.5~7.0	V
DC Output Voltage	V <sub>OUT</sub>	$-0.5 \sim V_{CC} + 0.5$	٧
Input Diode Current	I <sub>IK</sub>	-20	mA
Output Diode Current	I <sub>OK</sub>	± 20	mA
DC Output Current	I <sub>OUT</sub>	± 25	mA
DC V <sub>CC</sub> /Ground Current	I <sub>CC</sub>	± 50	mA
Power Dissipation	P <sub>D</sub>	180	mW
Storage Temperature	T <sub>stg</sub>	<b>−65~150</b>	°C

# **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	$V_{cc}$	2.0~5.5	٧
Input Voltage	VIN	0~5.5	٧
Output Voltage	V <sub>OUT</sub>	0~V <sub>cc</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	dt/dv	$0\sim100 \ (V_{CC}=3.3\pm0.3V)$ $0\sim20 \ (V_{CC}=5\pm0.5V)$	ns / V

### DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION		V <sub>cc</sub>	Ta = 25°C		С	Ta = − 40~		UNIT		
TAKAWILTEK	3 TIVIBOL			(V)	MIN.	TYP.	MAX.	MIN.	MAX.	ONIT		
High - Level	.,			2.0	1.50	_	_	1.50	_			
Input Voltage	V <sub>IH</sub>			3.0~ 5.5	$V_{cc} \times 0.7$	1	_	$V_{cc} \times 0.7$	_	V		
Low - Level				2.0		_	0.50	_	0.50			
Input Voltage	V <sub>IL</sub>			3.0~ 5.5	1	ı	$V_{cc} \times 0.3$	_	$V_{cc} \times 0.3$	V		
	V <sub>OH</sub>	.,	$I_{OH} = -50\mu A$	2.0	1.9	2.0	-	1.9	_			
High - Level Output Voltage		V <sub>I N</sub> =		3.0 4.5	2.9 4.4	3.0 4.5	_	2.9 4.4	_	V		
		V <sub>IH</sub> or V <sub>IL</sub>	$I_{OH} = -4mA$ $I_{OH} = -8mA$	3.0 4.5	2.58 3.94	_	_	2.48 3.80	_			
Low - Level Output Voltage	V <sub>OL</sub>				I <sub>OL</sub> = 50μA	2.0 3.0		0.0 0.0	0.1 0.1	_	0.1 0.1	
		$V_{IN} = V_{IH}$	OL 117	4.5		0.0	0.1	_	0.1	V		
			$I_{OL} = 4mA$ $I_{OL} = 8mA$	3.0 4.5		1 1	0.36 0.36	_	0.44 0.44			
Input Leakage Current	I <sub>I N</sub>	$V_{IN} = 5.5V$ or GND		0~5.5	-		±0.1	_	± 1.0			
Quiescent Supply Current	I <sub>cc</sub>	$V_{IN} = V_{CC}$ or GN	5.5			2.0	_	20.0	$\mu$ A			

# AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3ns$ )

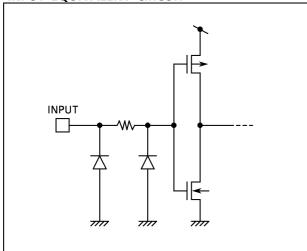
PARAMETER	CVMIDOL	TEST CONDITION		Ta = 25°C			Ta = -40~85°C		LINIT	
PARAIVIETER	SYMBOL		V <sub>CC</sub> (V)	CL (pF)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
	t <sub>pLH</sub> t <sub>pHL</sub>	Ι,	3.3 ± 0.3	15	_	4.6	6.6	1.0	8.0	ns
Propagation Delay Time			3.3 ± 0.3	50	_	7.1	10.1	1.0	11.5	
			5.0 ± 0.5	15		3.3	5.0	1.0	6.0	
				50	_	4.8	7.0	1.0	8.0	
Input Capacitance	C <sub>I N</sub>				_	4	10	_	10	nE
Power Dissipation Capacitance	C <sub>PD</sub>	(	Note 1)		_	19	_	_	_	pF

Note (1)  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

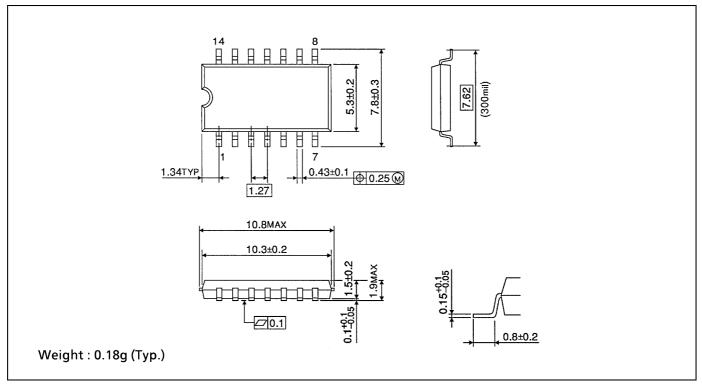
$$I_{CC \text{ (opr.)}} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 2 \text{ (per Gate)}$$

# **INPUT EQUIVALENT CIRCUIT**



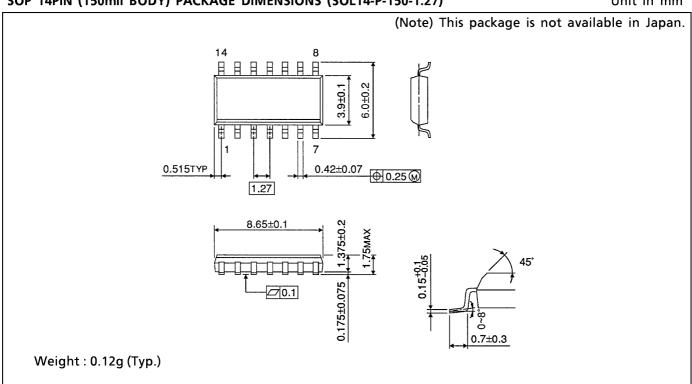
## SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm



# SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150-1.27)

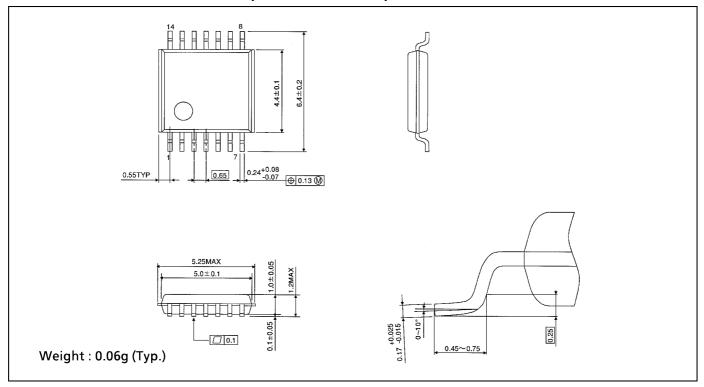
Unit in mm



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# TSSOP 14PIN PACKAGE DIMENSIONS (TSSOP14-P-0044-0.65)

Unit in mm



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